

Appl. No. 10/065,432
Amdt. dated November 12, 2004
Request for Continued Examination

REMARKS/ARGUMENTS

1. Request for continued examination:

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The Applicant respectfully requests continued examination of the above-indicated application as per 37 CFR §1.114.

2. Amendments to the specification:

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The title of the present application is amended to correspond with the amendments to the claims so as to be clearly indicative of the invention to which the claims are directed. No new matter is introduced by the amendments in the specification. Allowance of the amended
15 specification is respectfully requested.

3. Amendments to the claims:

In claims 1 and 21, the preambles thereof are amended to
20 emphasize the outstanding feature of the present invention is to introduce the steps for monitoring the quality of an oxide layer into the method of manufacturing a semiconductor device having the oxide layer. These amendments are entirely supported by the disclosure. For example, paragraph [0004] recites that the semiconductor devices
25 include MOS transistors, non-volatile memory and flash memory. Paragraph [0021] recites that the present invention examines the oxide layer quality with an in-line monitor. Paragraph [0033] recites the steps for forming the semiconductor devices in both a testing area and a normal product area. In addition, paragraphs [0034] and [0048] further
30 recite that the steps of providing swing time-dependent DC ramping voltages and measuring leakage currents are performed in a production line. It is obvious that the steps for monitoring the oxide layer quality

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can be introduced into the method of manufacturing the semiconductor devices according to the present application. Consideration of the amended claims 1 and 21 is respectfully requested.

5 Claims 10, 11, 15, 17, 19, 26, 34, 35, 39, 41, and 43 are amended to correct minor grammatical informalities identified in the claims. No new matter is introduced. Allowance of the amended claims is respectfully requested.

10 As claims 2-20 and 22-43 are dependent upon the amended claims 1 and 21, they should be allowed if the amended claims 1 and 21 are allowed. Consideration of claims 2-20 and 22-43 is therefore requested.

15 Respectfully submitted,



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20 Winston Hsu, Patent Agent No. 41,526

P.O. BOX 506

Merrifield, VA 22116

U.S.A.

Voice Mail: 302-729-1562

25 Facsimile: 806-498-6673

e-mail : winstonhsu@naipo.com

(Please contact me by voice mail if you need a telephone communication.)